



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: W. Thomas Novak

Attorney Docket No.: NIKOP037

Application No.: 10/764,377

Examiner: H. Nguyen

Filed: January 22, 2004

Group: 2851

Title: INTERFEROMETER SYSTEM FOR
MEASURING A HEIGHT OF WAFER STAGE

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on June 20, 2005 in an envelope addressed to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.

Signed: _____

Deborah Neill

**SEPARATE LETTER TO THE OFFICIAL DRAFTSMAN
REQUESTING ENTERING OF FORMAL DRAWINGS
(MPEP 608.02(p))**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In response to the objections made due to informalities in the original drawings (or to corrections approved by the Examiner), enclosed are substitute (formal) drawings for the above-identified patent application. If the Draftsman has any question concerning these drawings, he or she is respectfully requested to contact the undersigned.

Respectfully submitted,

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